

# Agilent HCPL-817

## Phototransistor Optocoupler

### High Density Mounting Type

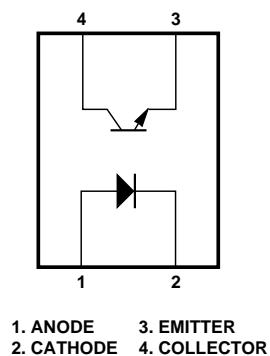
### Data Sheet

#### Description

The HCPL-817 contains a light emitting diode optically coupled to a phototransistor. It is packaged in a 4-pin DIP package and available in wide-lead spacing option and lead bend SMD option. Input-output isolation voltage is 5000 Vrms. Response time,  $t_r$ , is typically 4  $\mu$ s and minimum CTR is 50% at input current of 5 mA.

#### Functional Diagram

PIN NO. AND INTERNAL CONNECTION DIAGRAM



#### Ordering Information

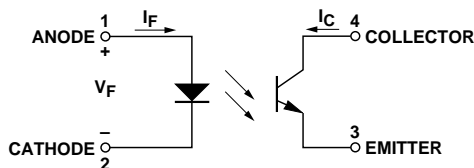
Specify part number followed by Option Number (if desired).

HCPL-817-XXX

Option Number

060 = VDE0884 Option  
W00 = 0.4" Lead Spacing Option  
300 = Lead Bend SMD Option  
500 = Tape and Reel Packaging Option  
00A = Rank Mark A  
00B = Rank Mark B  
00C = Rank Mark C  
00D = Rank Mark D  
00L = Rank Mark L

#### Schematic



#### Features

- Current Transfer Ratio (CTR: min. 50% at  $I_F = 5$  mA,  $V_{CE} = 5$  V)
- High input-output isolation voltage ( $V_{iso} = 5000$  Vrms)
- Response time ( $t_r$ : typ., 4  $\mu$ s at  $V_{CE} = 2$  V,  $I_C = 2$  mA,  $R_L = 100 \Omega$ )
- Compact dual-in-line package
- UL approved
- CSA approved
- VDE approved
- Options available:
  - Leads with 0.4" (10.16 mm) spacing (W00)
  - Leads bends for surface mounting (300)
  - Tape and reel for SMD (500)
  - VDE 0884 approvals (060)

#### Applications

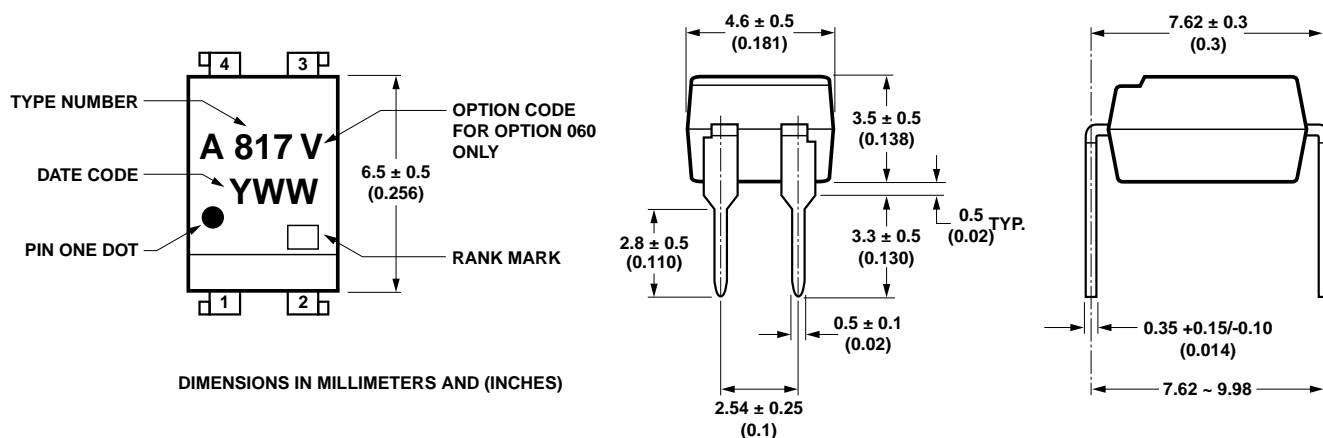
- Signal transmission between circuits of different potentials and impedances
- I/O interfaces for computers
- Feedback circuit in power supply

**CAUTION:** It is advised that normal static precautions be taken in handling and assembly of this component to prevent damage and/or degradation which may be induced by ESD.

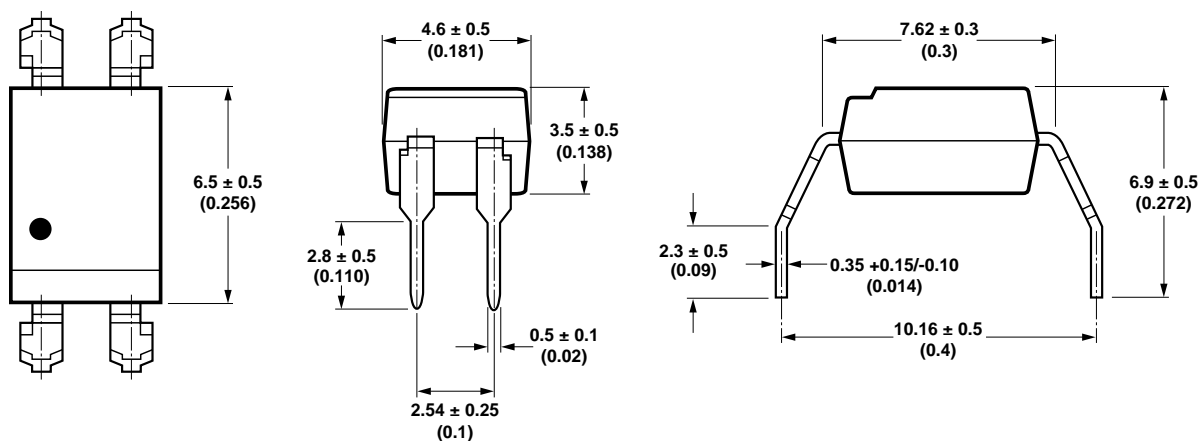


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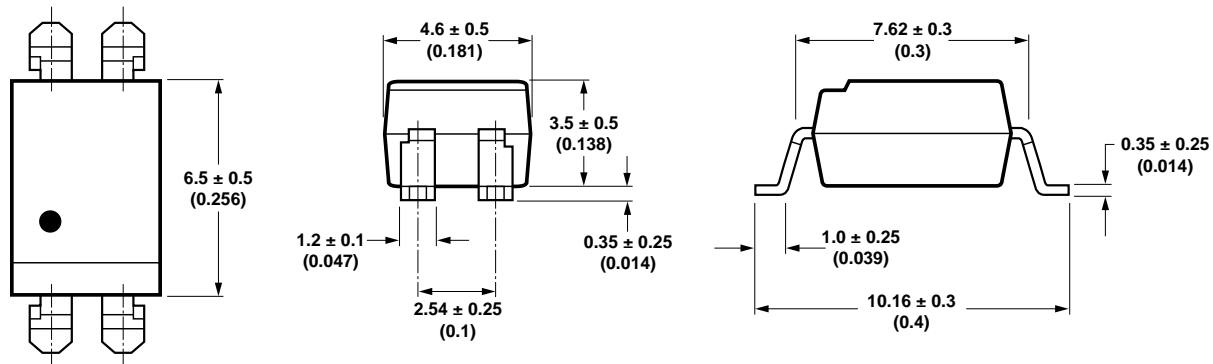
## Package Outline Drawings



## Package Outline – Option W00



## Package Outline – Option 300



**Absolute Maximum Ratings (T<sub>A</sub> = 25°C)**

Storage Temperature, T <sub>S</sub>	–55°C to +125°C
Operating Temperature, T <sub>A</sub>	–30°C to +100°C
Lead Solder Temperature, max. (1.6 mm below seating plane)	260°C for 10 s
Average Forward Current, I <sub>F</sub>	50 mA
Reverse Input Voltage, V <sub>R</sub>	6 V
Input Power Dissipation, P <sub>I</sub>	70 mW
Collector Current, I <sub>C</sub>	50 mA
Collector-Emitter Voltage, V <sub>CE0</sub>	35 V
Emitter-Collector Voltage, V <sub>ECO</sub>	6 V
Collector Power Dissipation	150 mW
Total Power Dissipation	200 mW
Isolation Voltage, V <sub>iso</sub> (AC for 1 minute, R.H. = 40 ~ 60%)	5000 Vrms

**Electrical Specifications (T<sub>A</sub> = 25°C)**

Parameter	Symbol	Min.	Typ.	Max.	Units	Test Conditions
Forward Voltage	V <sub>F</sub>	–	1.2	1.4	V	I <sub>F</sub> = 20 mA
Reverse Current	I <sub>R</sub>	–	–	10	μA	V <sub>R</sub> = 4 V
Terminal Capacitance	C <sub>t</sub>	–	30	250	pF	V = 0, f = 1 KHz
Collector Dark Current	I <sub>CEO</sub>	–	–	100	nA	V <sub>CE</sub> = 20 V
Collector-Emitter Breakdown Voltage	BV <sub>CEO</sub>	35	–	–	V	I <sub>C</sub> = 0.1 mA
Emitter-Collector Breakdown Voltage	BV <sub>ECO</sub>	6	–	–	V	I <sub>E</sub> = 10 μA
Collector Current	I <sub>C</sub>	2.5	–	30	mA	I <sub>F</sub> = 5 mA, V <sub>CE</sub> = 5 V,
*Current Transfer Ratio	CTR	50	–	600	%	R <sub>BE</sub> = ∞
Collector-Emitter Saturation Voltage	V <sub>CE(sat)</sub>	–	0.1	0.2	V	I <sub>F</sub> = 20 mA, I <sub>C</sub> = 1 mA
Response Time (Rise)	t <sub>r</sub>	–	4	18	μs	V <sub>CC</sub> = 2 V, I <sub>C</sub> = 2 mA
Response Time (Fall)	t <sub>f</sub>	–	3	18	μs	R <sub>L</sub> = 100 Ω
Cut-off Frequency	f <sub>c</sub>	–	80	–	KHz	V <sub>CC</sub> = 5 V, I <sub>C</sub> = 2 mA R <sub>L</sub> = 100 Ω, –3 dB
Isolation Resistance	R <sub>iso</sub>	5 x 10 <sup>10</sup>	1 x 10 <sup>11</sup>	–	Ω	DC 500 V 40 ~ 60% R.H.
Floating Capacitance	C <sub>f</sub>	–	0.6	1.0	pF	V = 0, f = 1 MHz

$$* \text{CTR} = \frac{I_C}{I_F} \times 100\%$$

Rank Mark	CTR (%)	Conditions
L	50 ~ 100	I <sub>F</sub> = 5 mA, V <sub>CE</sub> = 5 V, T <sub>A</sub> = 25°C
A	80 ~ 160	
B	130 ~ 260	
C	200 ~ 400	
D	300 ~ 600	

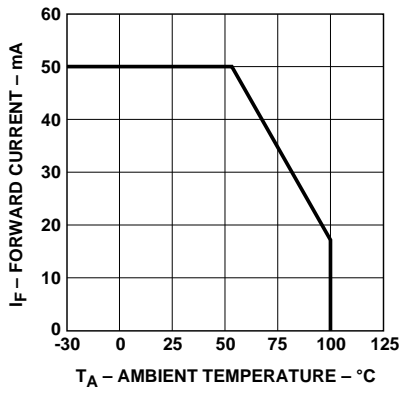


Figure 1. Forward current vs. temperature.

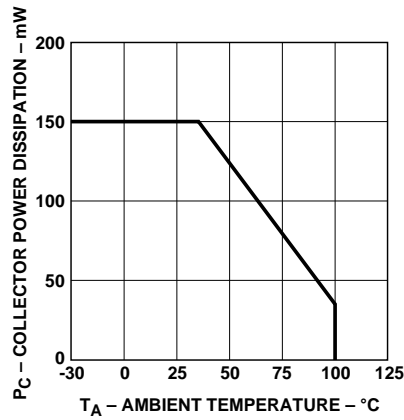


Figure 2. Collector power dissipation vs. temperature.

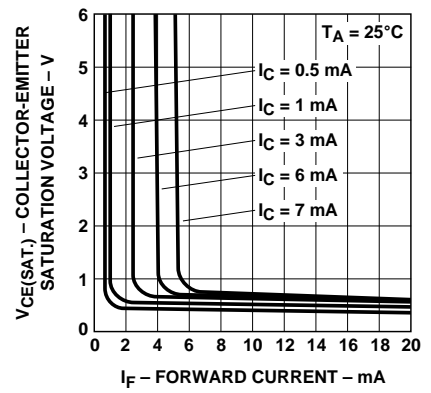


Figure 3. Collector-emitter saturation voltage vs. forward current.

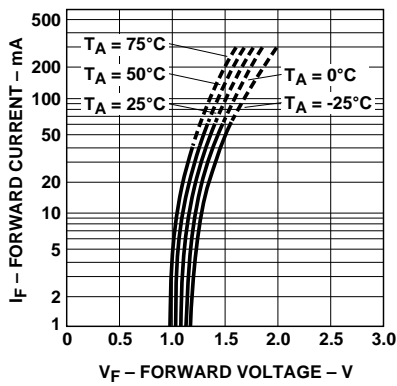


Figure 4. Forward current vs. forward voltage.

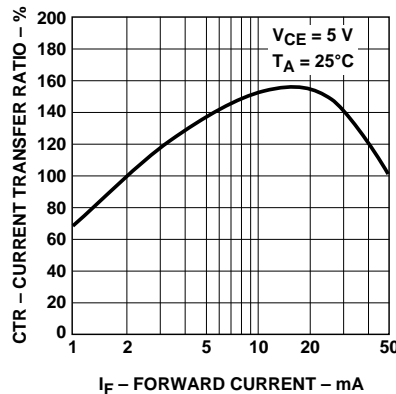


Figure 5. Current transfer ratio vs. forward current.

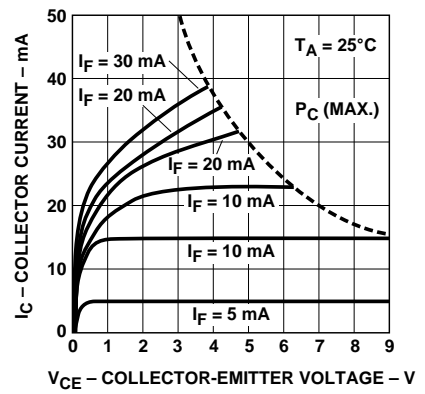


Figure 6. Collector current vs. collector-emitter voltage.

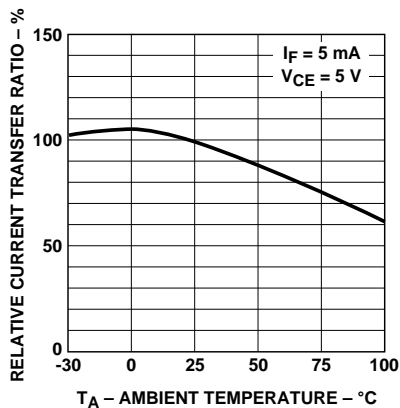


Figure 7. Relative current transfer ratio vs. temperature.

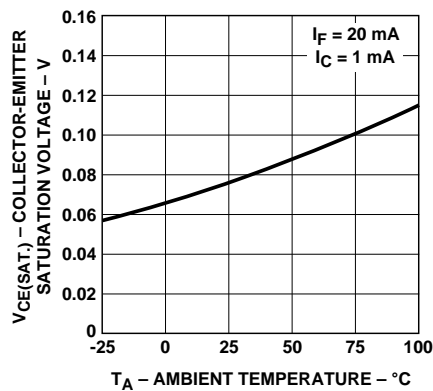


Figure 8. Collector-emitter saturation voltage vs. temperature.

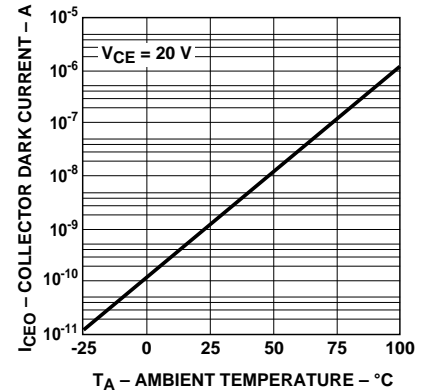


Figure 9. Collector dark current vs. temperature.

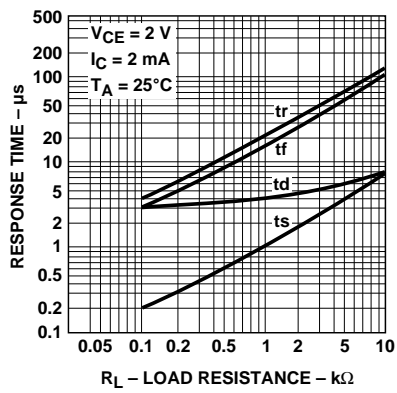


Figure 10. Response time vs. load resistance.

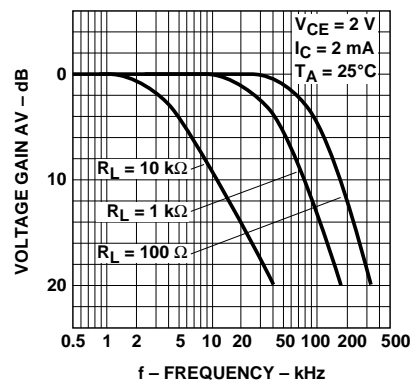
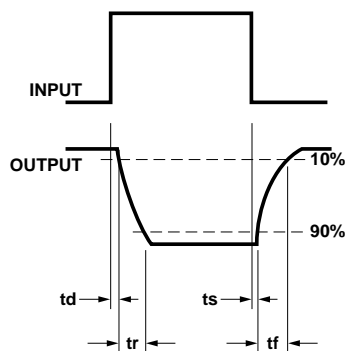
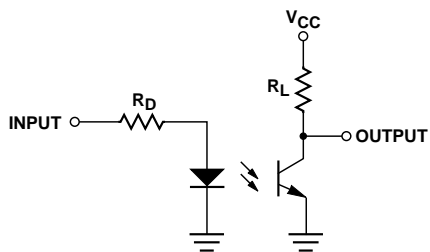
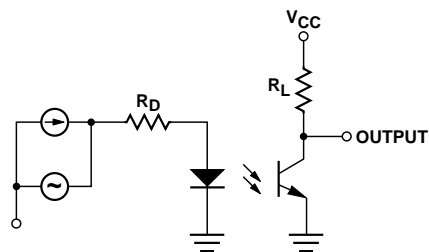


Figure 11. Frequency response.

### Test Circuit for Response Time



### Test Circuit for Frequency Response



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